# **STL3N65M2**



# N-channel 650 V, 1.6 Ω typ., 2.3 A MDmesh™ M2 Power MOSFET in a PowerFLAT™ 3.3x3.3 HV package

Datasheet - production data

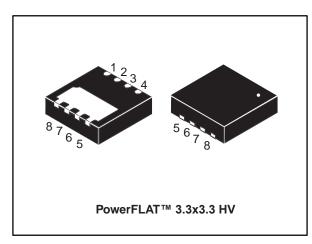
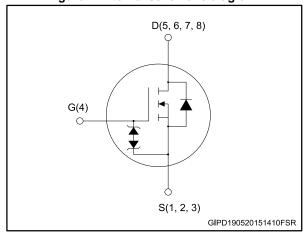


Figure 1: Internal schematic diagram



#### **Features**

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	ΙD
STL3N65M2	650 V	1.8 Ω	2.3 A

- Extremely low gate charge
- Excellent output capacitance (Coss) profile
- 100% avalanche tested
- Zener-protected

## **Application**

Switching applications

## **Description**

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary** 

Order code	Marking	Package	Packing
STL3N65M2	3N65M2	PowerFLAT™ 3.3x3.3 HV	Tape and reel

Contents STL3N65M2

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STL3N65M2 Electrical ratings

# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage	650	V
$V_{GS}$	Gate-source voltage	± 25	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	2.3	Α
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	1.45	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>amb</sub> = 25 °C	0.7	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>amb</sub> = 100 °C	0.43	Α
I <sub>DM</sub> <sup>(2)</sup> (3)	Drain current (pulsed)	2.8	Α
P <sub>TOT</sub> (2)	Total dissipation at T <sub>amb</sub> = 25 °C	2	W
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>C</sub> = 25 °C	22	W
las	Avalanche current, repetitive or not-repetitive <sup>(3)</sup>	0.3	Α
E <sub>AS</sub>	Single pulse avalanche energy (4)	70	mJ
dv/dt (5)	Peak diode recovery voltage slope	15	V/ns
T <sub>J</sub> T <sub>stg</sub>	Operating junction temperature range Storage temperature range -55 to 15		°C

#### Notes:

**Table 3: Thermal resistance** 

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max.	5.6	°C/W
R <sub>thj-amb</sub> (1)	Thermal resistance junction-amb max.	62.5	°C/W

#### Notes:

 $<sup>\</sup>ensuremath{^{(1)}} The value is rated according <math display="inline">R_{thj\text{-}case}.$ 

 $<sup>\</sup>ensuremath{^{(2)}}\xspace$  When mounted on FR-4 board of 1 inch², 2 oz Cu, t < 10 s.

 $<sup>^{(3)}</sup>$ Pulse width limited by  $T_{\text{jmax.}}$ 

 $<sup>^{(4)}</sup>Starting~T_j$  = 25 °C,  $I_D$  =  $I_{AS},~V_{DD}$  = 50 V.

 $<sup>^{(5)}</sup>I_{SD} \leq 2.3$  A, dv/dt  $\leq 400$  A/µs,VDS peak  $\leq V_{(BR)DSS},$  VDD = 80%  $V_{(BR)DSS}.$ 

 $<sup>^{(1)}</sup>$ When mounted on FR-4 board of 1 inch<sup>2</sup>, 2 oz Cu, t < 10 s.

Electrical characteristics STL3N65M2

## 2 Electrical characteristics

(T<sub>CASE</sub> = 25 °C unless otherwise specified)

Table 4: On/off-states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage (V <sub>GS</sub> = 0 V)	I <sub>D</sub> = 1 mA	650			V
IDSS	Zero-gate voltage drain current (V <sub>GS</sub> = 0 V)	V <sub>DS</sub> = 650 V			1	μΑ
I <sub>GSS</sub>	Gate body leakage current (V <sub>DS</sub> = 0 V)	V <sub>GS</sub> = ± 25 V			±10	μΑ
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static drain-source on-resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1 A		1.6	1.8	Ω

Table 5: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
Ciss	Input capacitance		-	155	1	pF
Coss	Output capacitance	V <sub>DS</sub> = 100 V, f = 1 MHz, V <sub>GS</sub> = 0 V	-	8	ı	pF
C <sub>rss</sub>	Reverse transfer capacitance	750 = 766 V, T = 7 Mil 12, V66 = 6 V	-	0.2	ı	pF
Coss eq.	Output equivalent capacitance	$V_{GS} = 0$ , $V_{DS} = 0$ V to 520 V	-	18	-	pF
Rg	Gate input resistance	f = 1 MHz gate DC bias = 0 test signal level = 20 mV open drain	ı	8.5	ı	Ω
$Q_g$	Total gate charge	V <sub>DD</sub> = 520 V, I <sub>D</sub> = 2.3 A	-	5	-	nC
$Q_{gs}$	Gate-source charge	V <sub>GS</sub> = 10 V	-	1	-	nC
$Q_{gd}$	Gate-drain charge	(see Figure 15: "Test circuit for gate charge behavior")	-	1.7	-	nC

### Notes:

**Table 6: Switching times** 

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time	V <sub>DD</sub> = 325 V, I <sub>D</sub> = 1.15 A,	1	6	1	ns
tr	Rise time	$R_G = 4.7 \Omega$ , $V_{GS} = 10 V$	ı	3.4	ı	ns
t <sub>d(off)</sub>	Turn-off delay time	(see Figure 14: "Test circuit for resistive load switching times")	ı	17	ı	ns
t <sub>f</sub>	Fall time		-	21.5	-	ns

 $<sup>^{(1)}</sup>$ Coss eq. is defined as a constant equivalent capacitance giving the same charging time as Coss when VDS increases from 0 to 80% VDSS.

Table 7: Source-drain diode

Symbol	Parameter	Test conditions	Min	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current		-		2.3	А
I <sub>SDM</sub> <sup>(1)</sup>	Source-drain current (pulsed)		-		9.2	Α
V <sub>SD</sub> <sup>(2)</sup>	Forward on voltage	I <sub>SD</sub> = 2.3 A, V <sub>GS</sub> = 0	-		1.6	V
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 2.3 A, di/dt = 100 A/μs,	-	184		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 60 V (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	0.7		μC
I <sub>RRM</sub>	Reverse recovery current		-	7.6		Α
t <sub>rr</sub>	Reverse recovery time	I <sub>SD</sub> = 2.3 A, di/dt = 100 A/μs,	-	300		ns
Qrr	Reverse recovery charge	V <sub>DD</sub> = 60 V, T <sub>j</sub> = 150 °C (see Figure 16: "Test circuit for inductive load switching and diode recovery times")	-	1.1		μC
I <sub>RRM</sub>	Reverse recovery current		-	7.4		Α

#### Notes:

<sup>&</sup>lt;sup>(1)</sup>Pulse width limited by safe operating area.

 $<sup>^{(2)}\</sup>text{Pulsed:}$  pulse duration = 300  $\mu\text{s,}$  duty cycle 1.5%.

 $\vec{V}_{DS}(V)$ 

# 2.1 Electrical characteristics (curves)

single pulse

10<sup>1</sup>

10<sup>2</sup>

10°

10<sup>-3</sup>

Figure 3: Thermal impedance

Zth powerFLAT 3.3x3.3

0.2

0.2

0.2

0.05

0.01

Zth=k Rthj-amb-Rthj-amb

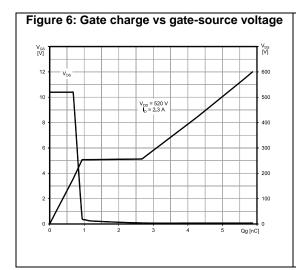


Figure 7: Static drain-source on-resistance  $R_{DS(on)}$   $V_{GS} = 10V$   $V_{GS}$ 

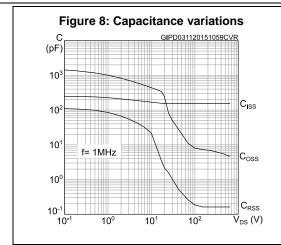


Figure 10: Normalized on-resistance vs temperature

R<sub>DS(on)</sub> GIPD031120151106RON

2.2 V<sub>GS</sub> = 10 V

1.8

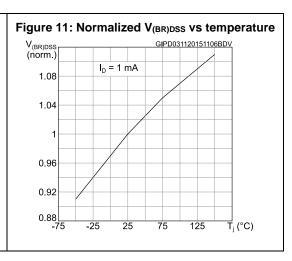
1.4

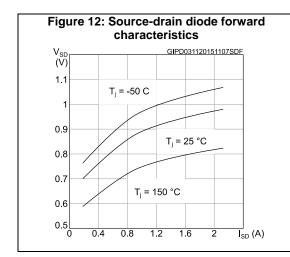
1

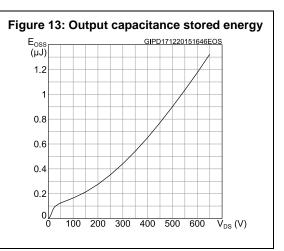
0.6

0.2

-75 -25 25 75 125 T<sub>j</sub> (°C)







Test circuits STL3N65M2

## 3 Test circuits

Figure 14: Test circuit for resistive load switching times

Figure 15: Test circuit for gate charge behavior

12 V 47 KΩ 100 Ω D.U.T.

12 V 47 KΩ VGD

14 VGD

14 VGD

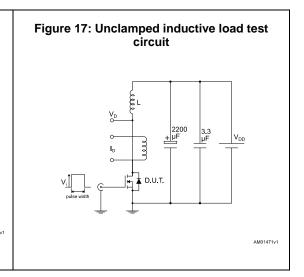
15 VGD

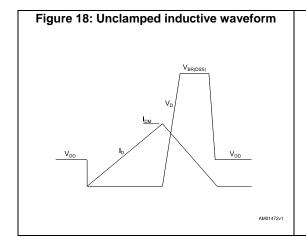
16 CONST 100 Ω D.U.T.

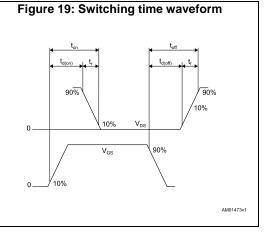
17 VGD

18 V

Figure 16: Test circuit for inductive load switching and diode recovery times







# 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

## 4.1 Power FLAT™ 3.3x3.3 HV package information

Figure 20: PowerFLAT™ 3.3x3.3 HV package outline

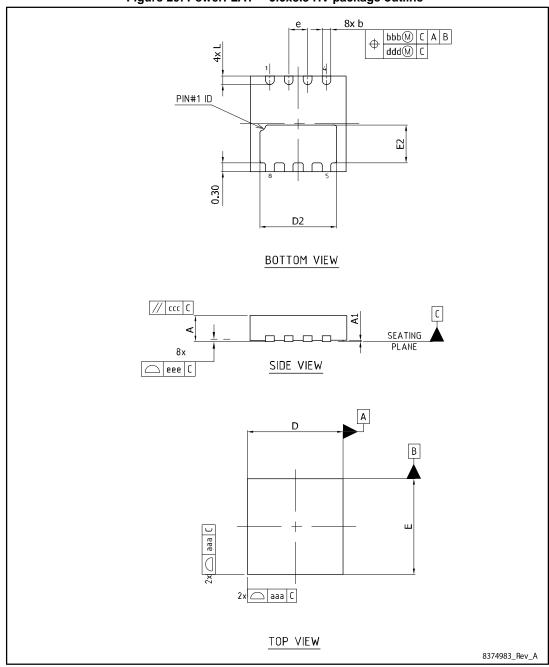
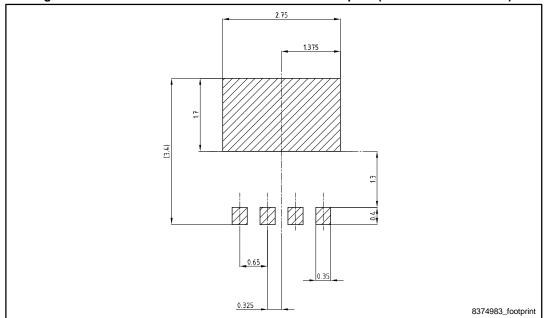


Table 8: PowerFLAT™ 3.3x3.3 HV package mechanical data

		ore iii paenage meename	
Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α	0.80	0.90	1.00
A1	0	0.02	0.05
b	0.25	0.30	0.40
D		3.30	
D2	2.50	2.65	2.75
е		0.65	
E		3.30	
E2	1.15	1.30	1.40
L	0.20	0.30	0.40
aaa		0.10	
bbb		0.10	
ccc		0.10	
ddd		0.05	
eee		0.08	

Figure 21: PowerFLAT™ 3.3x3.3 HV recommended footprint (dimensions are in mm)



STL3N65M2 Revision history

# 5 Revision history

**Table 9: Document revision history** 

Date	Revision	Changes	
19-May-2015	1	First release.	
17-Dec-2015	2	Updated title in cover page. Updated electrical characteristic section. Added electrical characteristic curves. Minor text changes.	
12-Apr-2016	3	Updated Section "Features".  Updated Table 2: "Absolute maximum ratings" and Table 5: "Dynamic".  Changed Figure 6: "Gate charge vs gate-source voltage".  Document status promoted from preliminary to production data.	

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